

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE
(Modified) PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.:
FIS920000191US1

SERIAL NO.:

INFORMATION DISCLOSURE
STATEMENT BY APPLICANT

APPLICANT: Christopher P. Ausschnitt

(Use several sheets if necessary)
(37 CFR 1.98(b))

FILING DATE:

GROUP:

10974 U.S. PTO
09/165148

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		PATENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE
DBE	AA	5,629,772	5/13/97	Ausschnitt			
DBE	AB	5,712,707	1/27/98	Ausschnitt et al.			
DBE	AC	5,731,877	3/24/98	Ausschnitt			
DBE	AD	5,756,242	5/26/98	Koizumi et al.			
DBE	AE	5,757,507	5/26/98	Ausschnitt et al.			
DBE	AF	5,776,645	7/7/98	Barr et al.			
DBE	AG	5,805,290	9/8/98	Ausschnitt et al.			
DBE	AH	5,914,784	6/22/99	Ausschnitt et al.			
DBE	AI	5,928,822	7/27/99	Rhyu			
DBE	AJ	5,949,547	9/7/99	Tseng et al.			
DBE	AK	5,953,128	9/14/99	Ausschnitt et al.			

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY OR PATENT OFFICE	CLASS	SUB- CLASS	TRANSLATION	
							YES	NO
	AL							
	AM							
	AN							
	AO							
	AP							

OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)

DBE	AQ	Intellectual Property Network, <i>Method for Measuring Semiconductor Lithographic Tool Focus and Exposure</i> , IBM Technical Disclosure Bulletin, July 1987, pages 516-518.
DBE	AR	Alexander Starikov, <i>Exposure Monitor Structure</i> SPIE Integrated Circuit Metrology, Inspection, and Process Control IV, Vol 1261, 1990, pages 315-324
	AS	

EXAMINER

DATE CONSIDERED

5/16/03

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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EXAMINER INITIAL		PATENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUB-CLASS	FILING DATE IF APPROPRIATE
DBE	AT	5,965,309	10/12/99	Ausschnitt et al.	_____	_____	_____
DBE	AU	5,968,693	10/19/99	Adams	_____	_____	_____
DBE	AV	5,976,740	11/2/99	Ausschnitt et al.	_____	_____	_____
DBE	AW	5,981,119	11/9/99	Adams	_____	_____	_____
DBE	AX	5,985,495	11/16/99	Okumura et al.	_____	_____	_____
DBE	AY	6,004,706	12/21/99	Ausschnitt et al.	_____	_____	_____
DBE	AZ	6,027,842	2/22/00	Ausschnitt et al.	_____	_____	_____
DBE	BA	6,128,089	10/3/00	Ausschnitt et al.	_____	_____	_____
DBE	BB	6,130,750	10/10/00	Ausschnitt et al.	_____	_____	_____
DBE	BC	6,137,578	10/24/00	Ausschnitt	_____	_____	_____
	BD						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY OR PATENT OFFICE	CLASS	SUB-CLASS	TRANSLATION	
							YES	NO
	BE							
	BF							
	BG							
	BH							
	BI							

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	BJ	
	BK	
	BL	

EXAMINER <i>D. Bey</i>	DATE CONSIDERED <i>5/16/03</i>
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